



Report No. SC1010487B-01-02

# EMC - TEST REPORT

## EUROPEAN STANDARD EN 60601-1-2: 2007 and IEC 60601-1-2: 2007

Test Report File No. : SC1010487B-01-02 Date of Issue: 17 January 2011

Model / Serial No. : MODEL: X10 / S/N: 101000003

Product Type : B-ALERT SYSTEM

Configuration Test Mode : CHARGE MODE

Applicant : ADVANCED BRAIN MONITORING SYSTEMS

Manufacturer : ADVANCED BRAIN MONITORING SYSTEMS

License holder : ADVANCED BRAIN MONITORING SYSTEMS

Address : 2850 Pio Pico Drive, Suite A  
: Carlsbad, CA 92008 – USA

Test Result : ☒ Positive ☐ Negative

Test Project Number : SC1010487B

Total pages - Test Report : 72

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*The client shall not use this report to claim product endorsement by NVLAP, NIST, or any agency of the U.S. Government.  
(TÜV SÜD America, Inc.'s (San Diego, California) NVLAP Lab Code: 100268-0.)*



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## TEST REGULATIONS:

The tests were performed according to the following regulations:

-----  
☒ - IEC 60601-1-2: 2007      ☒ - EN 60601-1-2: 2007  
-----

☒ - CISPR 11: 2009      ☐ - Class A      ☒ - Class B  
☒ - EN 55011: 2007; Amendment A2: 2007      ☐ - Class A      ☒ - Class B

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☐ - EN 61000-3-2: 2006  
☐ - IEC 61000-3-2: 2005; Amendment 1, 2008

☐ - EN 61000-3-3: 1995, Amendment 2: 2006  
☐ - IEC 61000-3-3: 2008  
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<input checked="" type="checkbox"/> - IEC 61000-4-2: 2008	EN 61000-4-2: 1995; Amendment 2, 2001
<input checked="" type="checkbox"/> - IEC 61000-4-3: 2008	EN 61000-4-3: 2006, Amendment 1, 2008
<input checked="" type="checkbox"/> - IEC 61000-4-4: 2007	EN 61000-4-4: 2004
<input type="checkbox"/> - IEC 61000-4-5: 2005	EN 61000-4-5: 2006
<input checked="" type="checkbox"/> - IEC 61000-4-6: 2008	EN 61000-4-6: 2007
<input checked="" type="checkbox"/> - IEC 61000-4-8: 2001	EN 61000-4-8: 1993; Amendment 1, 2001
<input type="checkbox"/> - IEC 61000-4-11: 2004	EN 61000-4-11: 2004

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**Note: Un-dark squares are not applicable**

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### Environmental Conditions In The Laboratory:

	<u>Actual</u>
Temperature	: 18 – 25 °C
Relative Humidity	: 42 – 55 %
Atmospheric Pressure	: 98.9 – 100.8 kPa

### Power Supply Utilized:

Power supply system	: 3.7 VDC
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### Symbol Definitions:

■ - Applicable  
□ - Not Applicable

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# **Test Conditions: CONDUCTED EMISSIONS (Interference Voltage)**

The **CONDUCTED EMISSIONS (Interference Voltage)** measurements were performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

■ - SR-3, Shielded Room, 12' x 20' x 8', Metal Chamber

## **Test Equipment Used:**

Model No.:	Prop. No.:	Description:	Manufacturer:	Serial No./Version No.:
ESHS 20	2534	EMI Test Receiver	Rohde & Schwarz	837055/003
CAT-20	8634	20 dB Attenuator	Mini-Circuits	--
FCC-LISN-50-25-2	6837	LISN	Fisher Custom Comm.	5025

ESHS 20	--	Test Software	Rohde & Schwarz	3.21
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Limit margin:	110 VAC / 60 Hz	<u>-10.2</u> dB	at	<u>1.025</u> MHz
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Limit margin:	230 VAC / 50 Hz	<u>-5.6</u> dB	at	<u>0.15</u> MHz
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## **Result:**

■ - Pass

☐ - Fail

**OPERATING MODE DESCRIPTION:** Charge Mode with Laptop USB Port

**Remarks:** One year calibration cycle for all test equipment.



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### Test Conditions: RADIATED EMISSIONS (Electric Field)

The **RADIATED EMISSIONS (Electric Field)** measurements were performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

■ - SR6 (3 and 10 meter Semi-Anechoic Chamber), San Diego, CA  
(Date of listing June 21, 2010. Site Verification NSA)

Testing was performed at a test distance of:

■ - 10 meters

### Test Equipment Used:

Model No.:	Prop. No.:	Description:	Manufacturer:	Serial No./Version No.:
3142C	SA1033	Antenna, Bilog	EMCO	44556
ESMI	SA1043,44	EMI Test Receiver	Rhode & Schwarz	848926/003
PAM-0202	SA1016	Pre-Amplifier	PAM	187
ES-K1	--	Test Software	Rohde & Schwarz	1.60 Service Pack 2

### Result:

■ - Pass

☐ - Fail

**OPERATING MODE DESCRIPTION:** Charge Mode with Laptop USB Port

**Remarks:** One year calibration cycle for all test equipment.



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**Test Conditions: CURRENT HARMONICS TEST**

The *CURRENT HARMONICS TEST* measurements were performed in the following location at the San Diego Testing Facility:

■ - Test not applicable
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**OPERATING MODE DESCRIPTION:**

<b>Remarks:</b>	Charge Mode through Laptop. Testing Not Applicable.
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**Test Conditions: VOLTAGE FLUCTUATION AND FLICKER TEST**

The *VOLTAGE FLUCTUATION AND FLICKER TEST* measurements were performed in the following location at the San Diego Testing Facility:

■ - Test not applicable
-------------------------

**OPERATING MODE DESCRIPTION:**

<b>Remarks:</b>	Charge Mode through Laptop. Testing Not Applicable.
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## Test Conditions: ELECTROSTATIC DISCHARGE (ESD)

The immunity against *ELECTROSTATIC DISCHARGE (ESD)* was performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

■ - TR-1, Test Room, 20.5' x 17' x 9'

### Test Equipment Used:

Model No.:	Prop. No.:	Description:	Manufacturer:	Serial No./Version No.:
NSG435	6783	ESD Simulator System	Schaffner	387
HCP	--	Horizontal Coupling Plane	TÜV SÜD America	--
VCP	--	Vertical Coupling Plane	TÜV SÜD America	--
NSG435	--	Test Software	Schaffner	--

### Test Specification:

Discharge Voltage (Air):	<input checked="" type="checkbox"/> - $\pm 2$ kV <input checked="" type="checkbox"/> - $\pm 4$ kV	<input type="checkbox"/> - $\pm 6$ kV <input checked="" type="checkbox"/> - $\pm 8$ kV	<input type="checkbox"/> - $\pm 15$ kV <input type="checkbox"/> - $\pm$ ____ kV
Discharge Voltage (Contact):	<input checked="" type="checkbox"/> - $\pm 2$ kV <input type="checkbox"/> - $\pm 3$ kV	<input checked="" type="checkbox"/> - $\pm 4$ kV <input type="checkbox"/> - $\pm 6$ kV	<input type="checkbox"/> - $\pm 8$ kV <input type="checkbox"/> - $\pm$ ____ kV
Discharge Impedance:	<input checked="" type="checkbox"/> - 330 $\Omega$ / 150 pF		
Discharge Repetition Rate:	<input checked="" type="checkbox"/> - $\geq 1$ sec.		
Number of Discharges:	<input checked="" type="checkbox"/> - 10 Positive <input checked="" type="checkbox"/> - 10 Negative		
Kind of Discharges:	Direct Discharge      Indirect Discharge <input checked="" type="checkbox"/> - Air <input checked="" type="checkbox"/> - HCP <input checked="" type="checkbox"/> - Contact <input checked="" type="checkbox"/> - VCP		
Polarity:	<input checked="" type="checkbox"/> - Positive <input checked="" type="checkbox"/> - Negative		
Location of Discharge:	<input checked="" type="checkbox"/> - See Data Record(s) <input type="checkbox"/> - Each location on the surface touchable by hand		

### Result:

<input checked="" type="checkbox"/> - Pass	<input type="checkbox"/> - Fail
<input checked="" type="checkbox"/> - No degradation of function	- Met Criterion A
<input checked="" type="checkbox"/> - Distortion of function	- Met Criterion B
<input type="checkbox"/> - Error of function	- Met Criterion C
<input type="checkbox"/> - Loss of function	- Unrecoverable Failure

**OPERATING MODE DESCRIPTION:** Charge Mode with Laptop USB Port

**Remarks:**

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## Test Conditions: RADIATED ELECTROMAGNETIC FIELDS

The immunity against **RADIATED ELECTROMAGNETIC FIELDS** was performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

☒ - SR-1, Shielded Room, 12' x 24' x 10', Metal, Compact Anechoic Chamber

### Test Equipment Used:

Model No.:	Prop No.:	Description:	Manufacturer:	Serial No./Version No.:
STLP9149	7535	Antenna, Log Periodic	Schwarzbeck	9149-022
AT5080M1	7508	Antenna, Log Periodic	Amplifier Research	0323556
FM 2000	6507	Isotropic Field Monitor	Amplifier Research	14677
FP 2000	6689	Isotropic Field Probe	Amplifier Research	14803
7005	7510	RF Power Amplifier	Ophir, 0.8 – 6GHz	1001
436A	6584	Power Meter	Hewlett Packard	1911A04722
8481A	6534	Power Sensor	Hewlett Packard	1926A27807
N5181A	7504	Signal Generator	Agilent	MY46240083
C3	--	Test Software	TÜV SÜD America	4.01.0 BUILD 0

### Test Specification:

Frequency Range: ☒ - 80 - 1000 MHz ☐ - 80 - 2500 MHz ☐ - 80 - 2700 MHz

Field Strength: ☐ - 1 V/m ☒ - 3 V/m ☐ - 10 V/m ☐ - \_\_\_\_ V/m

Distance Antenna - EUT: ☐ - 1 m ☒ - 3 m

Modulation: ☒ - AM: ☐ - FM: ☒ - 80 % ☒ - 10 Hz  
☐ - Un-Modulated ☐ - Pulse ON/OFF Duty Cycle: \_\_\_\_ %  
☒ - Sine Wave:

Step: ☐ - 1 second dwell ☒ - 3 seconds dwell ☒ - 1 %

Polarization of Antenna: ☒ - Horizontal ☒ - Vertical

### Result:

☒ - Pass ☐ - Fail

☒ - No degradation of function - Met Criterion A  
☐ - Distortion of function - Met Criterion B  
☐ - Error of function - Met Criterion C  
☐ - Loss of function - Unrecoverable Failure

**OPERATING MODE DESCRIPTION:** Charge Mode with Laptop USB Port

**Remarks:**

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## Test Conditions: FAST TRANSIENTS (BURST)

The immunity against *FAST TRANSIENTS (BURST)* was performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

☒ - TR-1, Test Room, 20.5' x 17' x 9'

### Test Equipment Used:

Model No.:	Prop. No.:	Description:	Manufacturer:	Serial No./Version No.:
EMC-PRO	6531	Advanced EMC Test System	Keytek	9912299
CEWare32	--	Test Software	Thermo Electron Corporation	4.0

### Test Specification:

Pulse Amplitude - AC Power Port:	<input checked="" type="checkbox"/> - 1.0 kV <input type="checkbox"/> - 4.0 kV	<input type="checkbox"/> - 2.0 kV <input checked="" type="checkbox"/> - 0.5 kV	
Pulse Amplitude - DC Power Port:	<input type="checkbox"/> - 1.0 kV <input type="checkbox"/> - 4.0 kV	<input type="checkbox"/> - 2.0 kV <input type="checkbox"/> - ____ kV	
Pulse Amplitude - Signal/Data Non control Port:	<input type="checkbox"/> - 0.5 kV <input type="checkbox"/> - 2.0 kV	<input type="checkbox"/> - 1.0 kV <input type="checkbox"/> - ____ kV	
Pulse Amplitude - Process Measurement & Control Port:	<input type="checkbox"/> - 0.5 kV <input type="checkbox"/> - 2.0 kV	<input type="checkbox"/> - 1.0 kV <input type="checkbox"/> - ____ kV	
Burst Frequency:	<input type="checkbox"/> - 2.5 kHz	<input checked="" type="checkbox"/> - 5.0 kHz	<input type="checkbox"/> - ____ kHz
Time of Coupling:	<input checked="" type="checkbox"/> - 60 seconds	<input type="checkbox"/> - ____ seconds	
Coupling Method:	<input checked="" type="checkbox"/> - Coupling/decoupling network	<input type="checkbox"/> - Coupling clamp	
Polarity:	<input checked="" type="checkbox"/> - Positive	<input checked="" type="checkbox"/> - Negative	

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**Test Conditions: FAST TRANSIENTS (BURST), continued**

**Location of Coupling:**

Name of lines:	<u>AC MAINS</u>	
Type of lines:	<input type="checkbox"/> - shielded	<input checked="" type="checkbox"/> - unshielded
Status of lines:	<input type="checkbox"/> - passive	<input checked="" type="checkbox"/> - active
Kind of transmission:	<input checked="" type="checkbox"/> - analog	<input type="checkbox"/> - digital
Length of lines:	<u>1 meter</u>	

**Result:**

<input checked="" type="checkbox"/> - Pass	<input type="checkbox"/> - Fail
<input checked="" type="checkbox"/> - No degradation of function	- Met Criterion A
<input type="checkbox"/> - Distortion of function	- Met Criterion B
<input type="checkbox"/> - Error of function	- Met Criterion C
<input type="checkbox"/> - Loss of function	- Unrecoverable Failure

**OPERATING MODE DESCRIPTION:** Charge Mode with AC adapter

**Remarks:**



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**Test Conditions: SURGE TRANSIENTS**

The immunity against *SURGE TRANSIENTS* was performed in the following location at the San Diego Testing Facility:

■ - Test not applicable
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<b>OPERATING MODE DESCRIPTION:</b>	
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<b>Remarks:</b>	Charge Mode through Laptop. Testing Not Applicable.
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## Test Conditions: CONDUCTED DISTURBANCE

The immunity against **CONDUCTED DISTURBANCE** was performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

■ - TR-, Test Room, 16' x 7.5' x 9'

### Test Equipment Used:

Model No.:	Prop. No.:	Description:	Manufacturer:	Serial No./Version No.:
FCC-801-M3-25	6514	Coupling/Decoupling Network	Fischer Custom Comm.	49
F2031-32MM	6830	EM Clamp	Fischer Custom Comm.	475
C5086	6591	Directional Coupler	Werlatone Inc.	2422
8648C	7544	Signal Generator	Hewlett Packard	3426A00529
500A100	6607	Power Amplifier	Amplifier Research	14938
436A	6436	Power Meter	Hewlett Packard	1918A05312
8482A	6826	Power Sensor	Hewlett Packard	3318A23844
50FHA0-006-250	7526	Attenuator	JFW	--
C3	--	Test Software	TESEQ	4.01.0 Build 0

### Test Specification:

Frequency Range: ☒ - 0.15 MHz - 80 MHz ☐ - 0.15 MHz - 230 MHz

Voltage Level (EMF): ☐ - 1 V ☒ - 3 V ☐ - 10 V ☐ - \_\_\_\_ V

Modulation: ☒ - AM: ☐ - FM: ☒ - 80 % ☒ - 1 kHz  
☐ - Un-Modulated ☐ - Pulse ON/OFF Duty Cycle: \_\_\_\_ %  
☒ - Sine Wave:

Step: ☐ - 1 second dwell ☒ - 3 seconds dwell ☒ - 1%

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**Test Conditions: CONDUCTED DISTURBANCE**, continued

**Location of Coupling:**

Name of lines:	USB Cable	
Type of lines:	<input checked="" type="checkbox"/> - shielded	<input type="checkbox"/> - unshielded
Status of lines:	<input type="checkbox"/> - passive	<input checked="" type="checkbox"/> - active
Kind of transmission:	<input type="checkbox"/> - analog	<input checked="" type="checkbox"/> - digital
Length of lines:	1 meter	

**Result:**

<input checked="" type="checkbox"/> - Pass	<input type="checkbox"/> - Fail
<input checked="" type="checkbox"/> - No degradation of function	- Met Criterion A
<input type="checkbox"/> - Distortion of function	- Met Criterion B
<input type="checkbox"/> - Error of function	- Met Criterion C
<input type="checkbox"/> - Loss of function	- Unrecoverable Failure

**OPERATING MODE DESCRIPTION:** Charge Mode with Laptop USB Port

**Remarks:**



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### Test Conditions: POWER FREQUENCY MAGNETIC FIELD

The immunity against *POWER FREQUENCY MAGNETIC FIELD* was performed in the following location at the San Diego Testing Facility:

☐ - Test not applicable

■ - TR-2, Test Room, 16' x 10' x 9'

### Test Equipment Used:

Model No.:	Prop. No.:	Description:	Manufacturer:	Serial No./Version No.:
1C-1m	6543	Loop Injection Coil	TÜV SÜD America	N/A
1000-8	6525	Magnetic Field Generator	TÜV SÜD America	N/A

■ - Test requires no software.

### Test Specification:

Frequency Range:	■ - 50 Hz	■ - 60 Hz	<input type="checkbox"/> - 400 Hz
Field level (EMF):	■ - 1 A/m <input type="checkbox"/> - 30 A/m	<input type="checkbox"/> - 3 A/m <input type="checkbox"/> - 100 A/m	<input type="checkbox"/> - 10 A/m <input type="checkbox"/> - ____ A/m
Short Field (1-3 sec):	<input type="checkbox"/> - 300 A/m	<input type="checkbox"/> - 1000 A/m	<input type="checkbox"/> - ____ A/m
Duration:	■ - 60 seconds	<input type="checkbox"/> - ____ seconds	
Axis of Orientation:	■ - X-axis	■ - Y-axis	■ - Z-axis

### Result:

■ - Pass	<input type="checkbox"/> - Fail
■ - No degradation of function	- Met Criterion A
<input type="checkbox"/> - Distortion of function	- Met Criterion B
<input type="checkbox"/> - Error of function	- Met Criterion C
<input type="checkbox"/> - Loss of function	- Unrecoverable Failure

**OPERATING MODE DESCRIPTION:** Charge Mode with Laptop USB Port

**Remarks:**





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### Test Conditions: VOLTAGE DIPS, INTERRUPTIONS & VARIATIONS

The immunity against *VOLTAGE DIPS, INTERRUPTIONS & VARIATIONS* was performed in the following location at the San Diego Testing Facility:

■ - Test not applicable
-------------------------

OPERATING MODE DESCRIPTION:	
-----------------------------	--

Remarks:	Charge Mode through Laptop. Testing Not Applicable.
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## Equipment Under Test (EUT) Test Operation Mode:

The equipment under test was operated under the following conditions during testing:

Charge Mode:

- Charge Mode with Laptop USB port
- Charge Mode with AC adapter (EFT Only)

## Configuration of the equipment under test:

- ☐ - See Constructional Data Form in Appendix B
- ☒ - See Product Information Form(s) in Appendix B

The following peripheral devices and interface cables were connected during the testing:

<input type="checkbox"/> - _____	Type: _____
<input type="checkbox"/> - _____	Type: _____
<input type="checkbox"/> - _____	Type: _____
<input type="checkbox"/> - _____	Type: _____
<input type="checkbox"/> - _____	Type: _____
<input type="checkbox"/> - _____	Type: _____
<input type="checkbox"/> - Unshielded power cable	
<input type="checkbox"/> - Unshielded cables	
<input type="checkbox"/> - Shielded cables	MPS. No.: _____
<input type="checkbox"/> - Customer specific cables	
<input type="checkbox"/> - _____	
<input type="checkbox"/> - _____	

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## GENERAL REMARKS:

Charge Mode:

- Charge Mode with Laptop USB port
- Charge Mode with AC adapter (EFT Only)

## SUMMARY:

The tests marked with darkened squares were performed according to the regulations cited on page 3

### ■ - Performed

The Equipment Under Test

■ - **Fulfills** all of the general approval requirements cited on page 3

## Statement of Measurement Uncertainty

The data and results referenced in this document are true and accurate. The test system for conducted emissions is defined as the LISN, tuned receiver or spectrum analyzer, and coaxial cable. This test system has a measurement uncertainty of  $\pm 1.8$  dB. The test system for radiated emissions is defined as the antenna, the pre-amplifier, the spectrum analyzer and the coaxial cable. This test system has a measurement uncertainty of  $\pm 4.8$  dB. The measurement uncertainty values for conducted and radiated emissions meet the requirements as expressed in CISPR 16-4-2. The equipment comprising the test systems is calibrated on an annual basis. The reader is cautioned that there is some measurement variability due to the tolerances of the test equipment that can contribute to a nominal product measurement uncertainty. Furthermore, component differences and manufacturing process variability of production units similar to that tested may result in additional product uncertainty. If necessary, refer to the test lab for the actual measurement uncertainty for specific tests.

Equipment Received Date: 30 November 2010

Testing Start Date: 30 November 2010

Testing End Date: 14 January 2011

- TÜV SÜD AMERICA, INC. -

Reviewing Engineer:



David Gray,  
(Senior EMC Engineer)

Test Engineer:



Lan Sayasane,  
(EMC Technician)



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## **Technical Documentation**

### **Test Data Sheets and Test Setup Drawing(s)**

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# TUV America Conducted Emissions

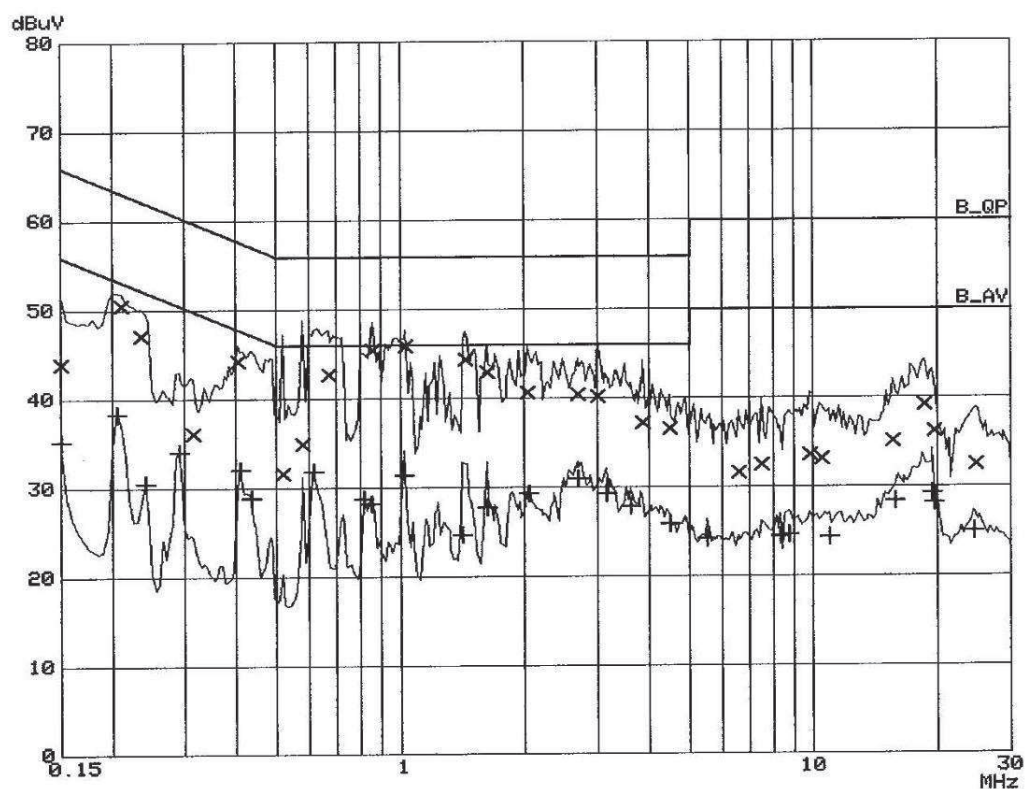
EUT: B-Alert X10  
 Manuf: Advanced Brain Monitoring Systems  
 Op Cond: Charge mode with Laptop USB port  
 Operator: Lan Sayasane  
 Test Spec: EN55011 Class B  
 Comment: 110Vac 60Hz Line 1  
 SC1010487  
 Date: 30. Nov 10 10:32

## Scan Settings (2 Ranges)

Frequencies			Receiver Settings						
Start	Stop	Step	IF BW	Detector	M-Time	Atten	Preamp	OpRge	
150k	1M	5k	10k	PK+AV	100ms	AUTO	LN OFF	60dB	
1M	30M	5k	10k	PK+AV	2ms	AUTO	LN OFF	60dB	

Transducer No.	Start	Stop	Name
1	9k	30M	20dBLISN

Final Measurement: x QP / + AV  
 Meas Time: 1 s  
 Subranges: 25  
 Acc Margin: 25dB



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TUV America  
Conducted Emissions

EUT: B-Alert X10  
Manuf: Advanced Brain Monitoring Systems  
Op Cond: Charge mode with Laptop USB port  
Operator: Lan Sayasane  
Test Spec: EN55011 Class B  
Comment: 110Vac 60Hz Line 1  
SC1010487  
Date: 30. Nov 10 10:32

Final Measurement Results:

Frequency MHz	QP Level dBuV	QP Limit dBuV
0.15000	44.0	66.0
0.21000	50.5	63.2
0.23500	47.1	62.3
0.31500	36.1	59.8
0.40500	44.2	57.8
0.52000	31.6	56.0
0.58000	34.9	56.0
0.67000	42.7	56.0
0.85500	45.4	56.0
1.02500	45.8	56.0
1.44000	44.3	56.0
1.62000	42.9	56.0
2.03500	40.6	56.0
2.68500	40.4	56.0
3.00000	40.2	56.0
3.86500	37.2	56.0
4.49000	36.6	56.0
6.58500	31.6	60.0
7.50500	32.5	60.0
9.77500	33.6	60.0
10.47500	33.2	60.0
15.61000	35.1	60.0
18.64500	39.2	60.0
19.66500	36.2	60.0
24.68500	32.5	60.0

Frequency MHz	AV Level dBuV	AV Limit dBuV
0.15000	35.2	56.0
0.20500	38.3	53.4
0.24000	30.5	52.1
0.29000	34.0	50.6
0.41000	32.1	47.7
0.43500	28.9	47.2
0.61500	31.9	46.0
0.81500	28.8	46.0
0.85000	28.2	46.0
1.02000	31.4	46.0
1.41000	24.6	46.0
1.62000	27.7	46.0
2.04500	29.2	46.0

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# TUV America Conducted Emissions

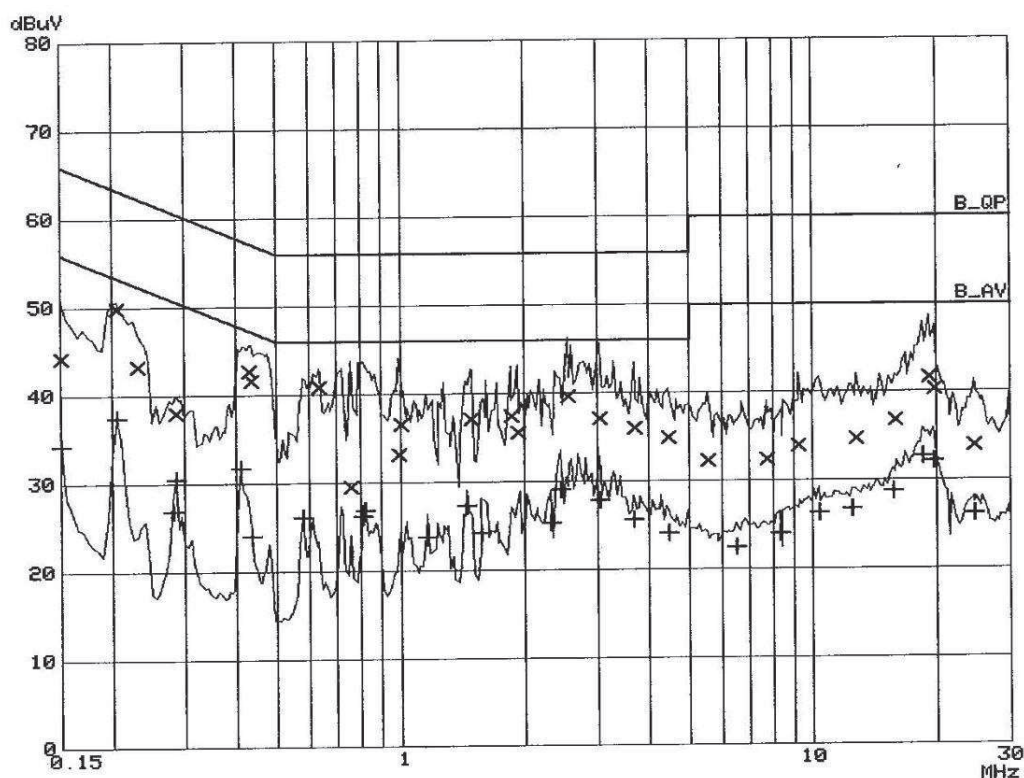
EUT: B-Alert X10  
Manuf: Advanced Brain Monitoring Systems  
Op Cond: Charge mode with Laptop USB port  
Operator: Lan Sayasane  
Test Spec: EN55011 Class B  
Comment: 110Vac 60Hz Line 2  
SC1010487  
Date: 30. Nov 10 10:43

## Scan Settings (2 Ranges)

Frequencies			Receiver Settings					
Start	Stop	Step	IF BW	Detector	M-Time	Atten	Preamp	OpRge
150k	1M	5k	10k	PK+AV	100ms	AUTO	LN OFF	60dB
1M	30M	5k	10k	PK+AV	2ms	AUTO	LN OFF	60dB

Transducer No.	Start	Stop	Name
1	9k	30M	20dBLISN

Final Measurement: x QP / + AV  
Meas Time: 1 s  
Subranges: 25  
Acc Margin: 25dB



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TUV America  
Conducted Emissions

EUT: B-Alert X10  
Manuf: Advanced Brain Monitoring Systems  
Op Cond: Charge mode with Laptop USB port  
Operator: Lan Sayasane  
Test Spec: EN55011 Class B  
Comment: 110Vac 60Hz Line 2  
SC1010487  
Date: 30. Nov 10 10:43

Final Measurement Results:

Frequency MHz	QP Level dBuV	QP Limit dBuV
0.15000	44.2	66.0
0.20500	49.8	63.4
0.23000	43.3	62.4
0.28500	38.0	60.7
0.43000	42.8	57.3
0.43500	41.6	57.2
0.63500	40.8	56.0
0.75500	29.5	56.0
0.99000	33.1	56.0
1.00000	36.6	56.0
1.48000	37.1	56.0
1.85500	37.4	56.0
1.92000	35.6	56.0
2.54500	39.6	56.0
3.04000	37.1	56.0
3.69500	36.0	56.0
4.45500	34.9	56.0
5.54500	32.2	60.0
7.73500	32.4	60.0
9.24500	33.9	60.0
12.74500	34.6	60.0
15.86000	36.7	60.0
19.12000	41.6	60.0
19.70500	40.3	60.0
24.56000	33.9	60.0

Frequency MHz	AV Level dBuV	AV Limit dBuV
0.15000	34.2	56.0
0.20500	37.4	53.4
0.28000	26.8	50.8
0.28500	30.5	50.7
0.41000	31.7	47.7
0.43500	23.9	47.2
0.58000	26.1	46.0
0.81000	26.2	46.0
0.82000	26.9	46.0
1.16000	23.8	46.0
1.44500	27.3	46.0
1.56500	24.2	46.0
2.31500	25.3	46.0

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